

SONY**CXB1140Q/Q-Y****Hex 2: 1 Multiplexer with Latch**

T-68-11*51

Description

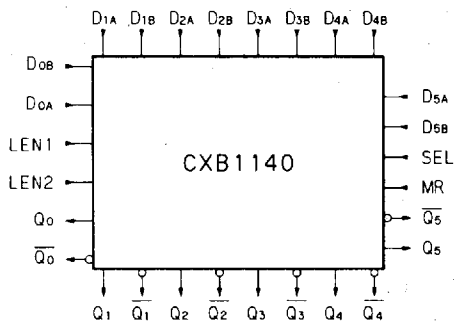
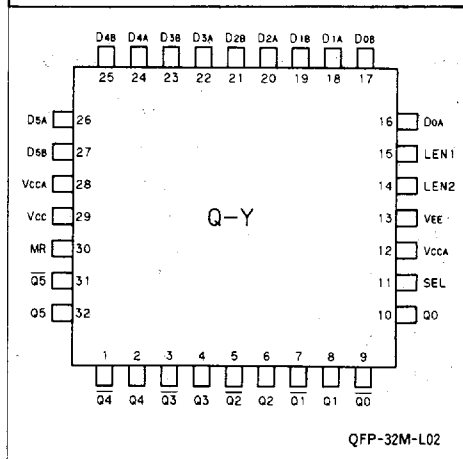
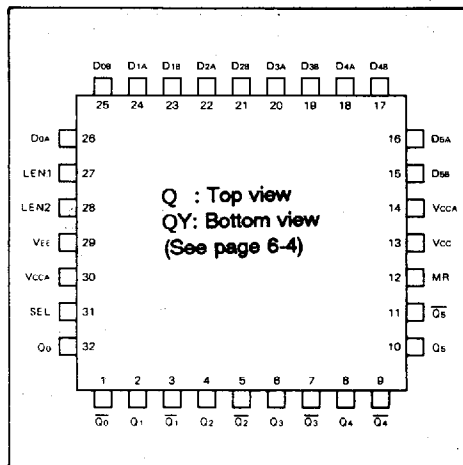
The CXB1140Q is an ultra high speed monolithic ECL IC, which contains six 2:1 multiplexers with transparent Latched outputs. The data select (SEL) input determines which data input is enabled. When both Latch enable (LEN1, LEN2) inputs are LOW, the Latch is transparent. The selected data is Latched on the positive transition of the Latch enable inputs. The Master Reset (MR) overrides all other control inputs and turns Q outputs to LOW.

Features

- Typical propagation delay time:
Tpd=780ps (Dn to Qn)
- Differential outputs
- Internal pull down resistors on input pins to maintain logic LOW level with the pins left open
- ECL 100K compatible I/O levels

Pin Names

D _{1A} , D _{1B}	Data inputs
Q _n , Q _n	Data outputs
SEL	Data Select input
LEN _n	Latch enable inputs
MR	Direct Master Reset input
V _{cc}	Circuit ground
V _{CCA}	Circuit ground for outputs
V _{EE}	Negative power supply

Logic Symbol**Pin Assignment**

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CXB1140Q/QY

DC Characteristics

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 $V_{EE} = -4.5V \pm 0.3V$, $V_{CC} = V_{CCA} = GND$, $V_{TT} = -2.0V$, $T_C = 0^\circ C$ to $+85^\circ C$

Item	Symbol	Test Condition	Min.	Typ.	Max.	Unit
Power supply current	I _{EE}		-133	-98	-68	mA

Note: Other DC characteristics; See pages 3-3 and 3-4.

AC Characteristics

 $V_{EE} = -4.5V \pm 0.3V$, $V_{CC} = V_{CCA} = GND$, $V_{TT} = -2.0V$, $T_C = 0^\circ C$ to $+85^\circ C$, $R_T = 50\Omega$ to V_{TT}

Item	Symbol	Input	Output	Test Condition	Min.	Typ.	Max.	Unit
Propagation delay time	T _{PLH}	D _{nA}	Q _n	LEN _n =L	570	770	1000	ps
		D _{nB}			580	780	1020	
	SEL	700			940	1220		
		720			960	1250		
	T _{PHL}	LEN _n		640	860	1120		
				640	860	1120		
	T _{PLH}	MR		700	930	1210		
				670	900	1170		
Gate-to-Gate skew	T _{SG-G}	D _{nA} , D _{nB}		LEN _n =L		60	100	
Set Up time	T _s	D, LEN _n			80			
		SEL, LEN _n			320			
Hold time	T _h	LEN _n , D			170			
		LEN _n , SEL			-70			
Release time	T _r	MR, LEN _n			310			
Min. Pulse width	T _{pw}	MR			430			
Rise time	T _{TLH}	D _{nA} , D _{nB}	20% to 80%			290	380	
Fall time	T _{THL}					270	340	

Note: AC test circuit; See pages 4-3, 4-4 and 4-5.

Truth Table

Select input	Outputs
SEL	Q _n
L	D _{nA}
H	D _{nB}

Inputs		Latch
LEN1	LEN2	
L	L	Transparent
H	X	Latch
X	H	Latch

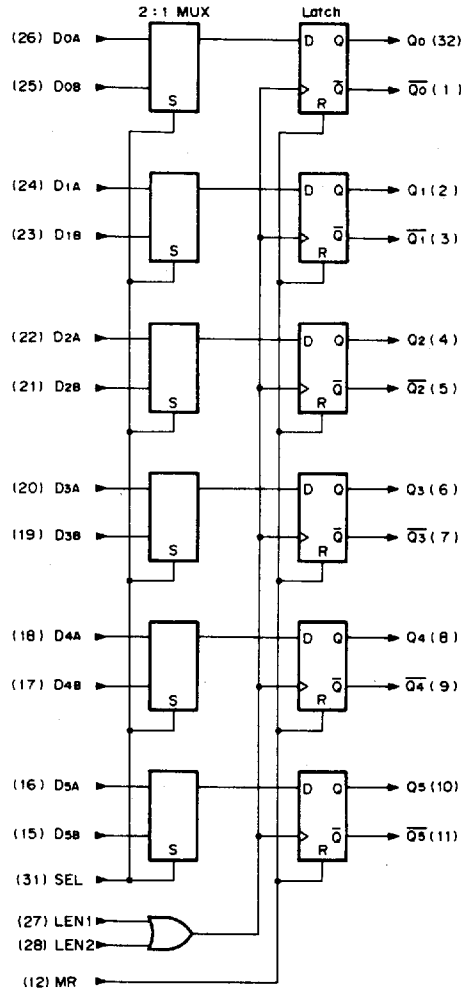
Note: H; HIGH voltage Level

L; LOW voltage Level

X; Don't care

Block Diagram

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Package Data

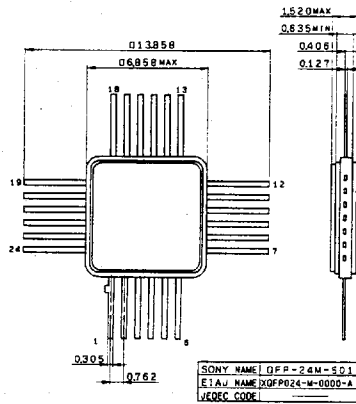
T-90-20

Package Outline

Unit: mm

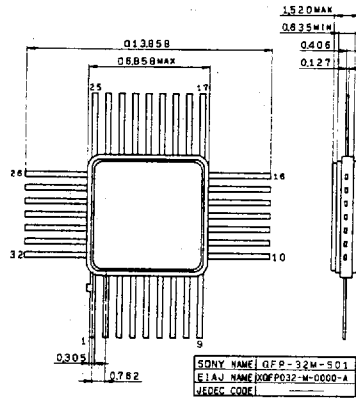
24pin QFP (QFP-24M-S01)

24pin QFP (Metal) 0.3g



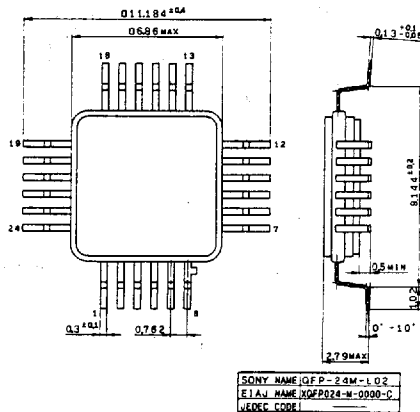
32pin QFP (QFP-32M-S01)

32pin QFP (Metal) 0.2g



24pin QFP (QFP-24M-L02)

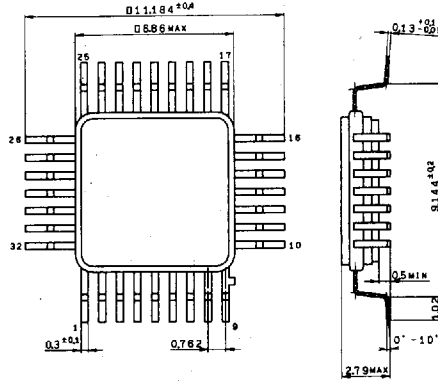
24pin QFP (Metal) 0.3g



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32pin QFP (QFP-32M-L02)

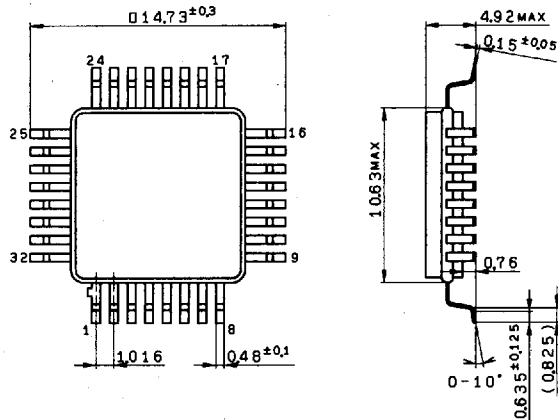
32pin QFP (Metal) 0.2g



SONY NAME	QFP-32M-L02
EIAJ NAME	XQFP032-M-0000-C
JEDEC CODE	

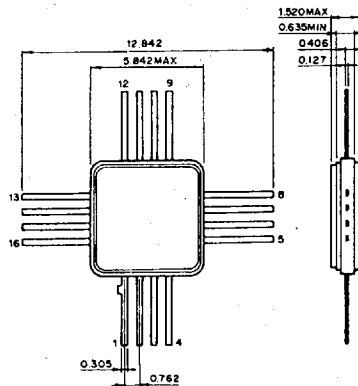
32pin QFP (QFP-32C-L01)

32pin QFP (Ceramic)



SONY NAME	QFP-32C-L01
EIAJ NAME	XQFP032-G-0000-A
JEDEC CODE	

16pin QFP



Package Data

Package Data	Page
1. 16 pin QFP	6-3
2. 24 pin QFP	6-3
3. 32 pin QFP	6-3
4. 24 pin QFP with formed lead	6-4
5. 32 pin QFP with formed lead	6-4

Package Data

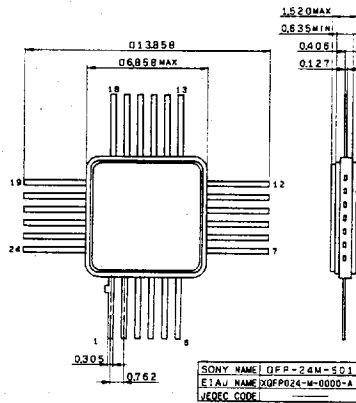
T-90-20

Package Outline

Unit: mm

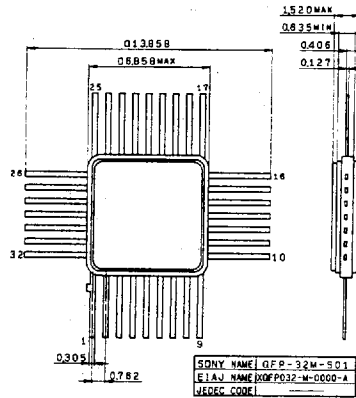
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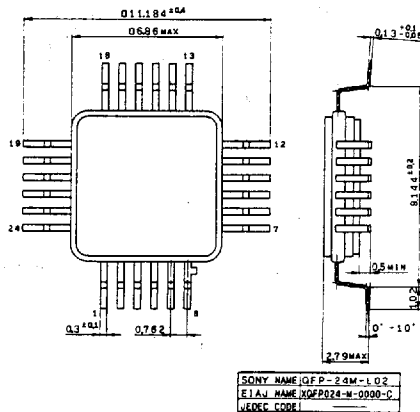
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32pin QFP (Metal) 0.2g



24pin QFP (QFP-24M-L02)

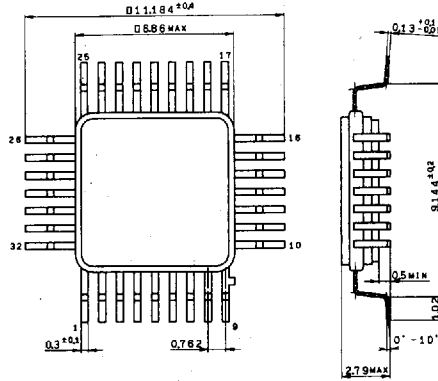
24pin QFP (Metal) 0.3g



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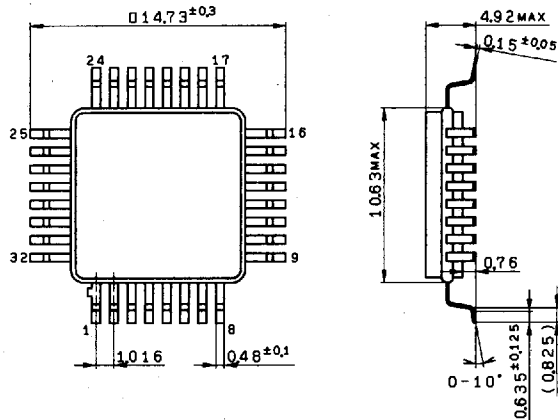
32pin QFP (Metal) 0.2g



SONY NAME	QFP-32M-L02
EIAJ NAME	XQFP032-M-0000-C
JEDEC CODE	

32pin QFP (QFP-32C-L01)

32pin QFP (Ceramic)



SONY NAME	QFP-32C-L01
EIAJ NAME	XQFP032-G-0000-A
JEDEC CODE	

16pin QFP

